

Empowering PMIC Validation in an Evolving Market

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Agenda

- NI Connect 2023: Technical Session
- Introduction & market trends (10 mins)
- ***NEW*** 300W PXI Power Instruments Deep-Dive (15 mins)
- Demo (10 mins)
- Q&A (remaining time)

PMIC Market | Trends

PMICs in **mobile**, **automotive**, **and industrial applications** driving needs for power density and efficiency

Top design considerations for today's PMIC landscape Designers are required to squeeze more with less space, while increasing efficiency and thermal performance Low EMI design can reduce filter size, cost, and complexity, especially in automotive and industrial applications Battery-operated systems are often in standby/sleep mode for long periods

- Excessive noise can harm sensitive applications and peripheral circuits (such as ADCs, AFEs, and clock sources)
- Good isolation management enhances system reliability, \geq simplifies EMI compliance, and reduces form factors

1. Increasing power density and efficiency

- 2. Lowering cost Electromagnetic Interference (EMI)
- 3. Lowering quiescent current extend battery and shelf life
- 4. Lowering Noise Enhancing precision
- Increasing Safety and Quality Isolation between 5. high and low voltage domains

PMIC and Automotive | Semiconductor Growth Leaders

Analog ICs:

- Second highest growth product category in Semiconductor market
- PMIC highest growth sub-type of analog ICs

By Application:

- Communications to maintain largest market share position ~37%
- Automotive poised for significant growth
 - CAGR 14.7%
 - Expected to make up for >25% of Analog IC market by 2026



Mobile PMICs | Trends Fast Charging

Extensive validation and testing needed for charger IC devices to ensure **performance**, **interoperability**, and **safety** meet industry standards



Higher Power Delivery (Speed)

ng **Test impact:**

 Support for ~100W+ charging becoming commonplace
 USB-PD 3.1 capable of 240W+

Capable HW up to 300W+ Increased importance of temperature and safety testing





Broad Ecosystem Support

Trend: 1. Growing need for charging ICs that support multiple protocols

Test impact:

 Greater need for interoperability testing across devices
 More protocols need to be tested



Intelligent Charging

Trend:

Trends:

 Intelligent charging that optimizes charging times and improve battery health
 Smaller form factors Test impact:

1. Increased importance of temperature and safety testing



Wide variety of charging standards in market

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Automotive PMICs | Trends Vehicle Electrification

Vehicle electrification necessitates **increased validation** and testing of automotive electronics, driving new PMIC capabilities for **reliable electric vehicles**



Batteries: Range & Efficiency

Trend:

- 1. Higher power PMICs needed for regulation of increased battery capacity
- 2. Efficient PMICs critical for **optimized system** efficiency during charging
- **3. Vehicle-to-Grid (V2G)** technology requires PMICs supporting safe and efficient bi-directional power flow for charge / discharge modes

Test impact:

Capable HW to validate and test higher power PMICs and support bi-directional power flow



Safety, ADAS, Infotainment: Complexity

Trend:

- 1. Demand for highly-integrated PMICs for Infotainment, ADAS, and Safety applications
- 2. Complex safety requirements necessitate extensive PMIC validation and testing

→ ISO26262, IEC60730, IEC61508

Test impact:

Scalable test & measurement platform with diverse instrumentation and robust software & data tools





Aligning Investments with Trends

Increasing Power Density and Efficiency

- 1. Mobile Fast Charging
 - 1. Proliferation of 65W-100W charging
 - 2. USB-PD 3.1 capable of 240W+
- 2. Automotive Vehicle Electrification
 - 1. EV battery architectures demanding higher power front-end (battery) PMICs
 - 2. Advancements in power density through SiC and GaN devices

NEW NI PXI 300W Instrumentation



NEW Power Semiconductor Reliability Solutions





Increasing Complexity from Design to Test

- 1. Broadened functionality of devices & systems
- 2. Stringent safety & reliability requirements
- 3. New technologies like wireless charging and V2G

NI Platform

Naturally suited for efficient and thorough PMIC Validation

1. Hardware



- 1. Simple and precise timing & synchronization
- 2. Cost-effective, scalable, flexible platform
- 3. Broad instrument portfolio (Digitizers, FGENs, Digital, DMMs, Power Supplies, E-Loads, SMUs, Switches)
- 2. Software
 - 1. Interactive and Automated Measurements (InstrumentStudio, TestStand, APIs)
 - 2. Data Ingestion, Management, and Spec Compliance Tools (DataStudio)
 - 3. System and Asset Utilization (SystemLink)

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High-Performance 300 W PXI Power Instruments

PXIe-4151 300 W Power Supply	PXIe-4051 300 W E-load
 1 channel, 2 PXI slots Up to 20 V / 25 A / 300W 60V variant (2024) 	1 channel, 3 PXI slotsUp to 60 V and 40 A
 Ranges Current: Full scale, 1 A, & 100 mA ranges (up to 10 nA resolution) Voltage: Full scale and 6 V ranges (up to 1 mV resolution) 	 Ranges Current: Full scale and 4 A ranges (up to 4 μA resolution) Voltage: Full scale and 6 V ranges (up to 30 μV resolution)

Common Features:

- Max sink/source power: 300 W
- Simultaneous I & V measurements
- DMM-like measurement accuracy
- 1.8 MS/s sample rate & 100 kS/s update rate
- Transient response tuning (SourceAdapt)
- Advanced sequencing (per-step properties)





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PXIe-4151

PXIe-4051



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Comparing Types of Programmable Power Instruments

"Basic" Power Supplies & E-loads

More affordable (more Watts per \$) Minimal or no measurement capabilities Accuracy of ~1% for setpoint Burdensome timing & synchronization options Basic programming API & minimal documentation Lacking application software for interactive tasks



High-Performance Power Supplies & E-loads

Premium power instruments Simultaneous DMM-class I & V measurements Accuracy of ~0.0x% (setpoint & measurements) Integrated PXI-class timing & synchronization Robust API, example programs, & documentation InstrumentStudio support for interactive actions



E.g. NI PXIe-415x Power Supplies & PXIe-405x E-loads

NI CONFIDENTIAL E.g. NI RMX-41xx Power Supplies & E-loads

Benefits of NI's 300 W PXI Instruments



PXIe-4051 | Functional Block Diagram

- User-programmable setpoints (all modes) and slew rates (CC, CV only)
- SourceAdapt allows user to control FlexLoop parameters:
 - Gain-bandwidth

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- Compensation frequency
- Pole-Zero ratio
- Slew rate control implemented by filter block
- Current sensed by measuring differential voltage across R_{sense}
- Controller acts on the gate of the load FET, behaving as a voltage-controlled resistance
- Other user-programmable parameters:
 - Voltage and current measurement range
 - Current and voltage limits



User I-V Compliance Limits

PXIe-4051 | SourceAdapt Control Loop

- Control is split into digital and analog domains
- Digital implementation allows custom-tuned system response
- SourceAdapt user-programmable parameters¹:
 - Integrator gain (GBW)
 - Compensation frequency
 - Pole-zero ratio
- SourceAdapt optimizes system response by:
 - Minimizing rise times
 - Reducing overshoot
 - Minimizing oscillations

¹CC, CV, and CP modes are each governed by a dedicated control loop that is switched in an out of the main loop path depending on the chosen operational mode. Each loop has physical units that correspond to the control variable e.g. the 'power' control loop has units of Watts.



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Demo Overview



Hardware Components:

- PXIe-4151 20V, 25A PPS
- PXIe-4051 60V, 40A e-load
- APS-4158/9 auxiliary power
- <u>LTM4676A</u> buck converter on <u>DC1811B-B</u> EVM
- DC1613A PMBus I2C/USB interface

Software Components:

- LabVIEW + NI-DCPower Driver API
- LTPowerPlay for digital control

Example Measurements:

- Efficiency
- Line/Load Regulation
- Load Transient

Give us your feedback! Quick 2 Question Survey

In the mobile app, click into the session you would like to provide feedback for



10:15 AM Multichannel RF Data Recording 11:15 AM and Analysis

Meeting Room 19A

Aerospace & Defense •
 Technical Session

10:15 AM Optimizing Validation Processes: 11:15 AM Building Complex Test Systems with Distributed I/O

- Meeting Room 19B
- Aerospace & Defense •
 Technical Session

10:15 AM Panel: Continuous Integration (Cl/ 11:15 AM CD)—Don't Leave Home without It

- Meeting Room 12A
- Programming Essentials Technical Session

10:15 AM Using Python and TestStand to 11:15 AM Boost Your Test Development

Ballroom G

 Product & Technology • Technical Session

10:15 AM What Does Left Shifting Test 11:15 AM Mean in the NI Ecosystem?

Meeting Room 18A
 Transportation - Technical Session

〈 Tue May 23

🛨 Add to Schedule 🛛 🏥 iCal 🛛 👤 Check In

Optimizing Validation Processes: Building Complex Test Systems with Distributed I/O

Tue May 23 10:15 AM - 11:15 AM

Map Meeting Room 19B Aerospace & Defense • Technical Session

Surveys

Take Session Survey

In this session, learn to improve efficiency and reduce non-recurring engineering costs in validation labs by connecting multiple distributed line-replaceable unit (LRU) test systems. Also learn how to abstract LRUs and construct complex test systems faster and more efficiently using existing distributed I/O and edge computation technology.

Click "Take the Session Survey"

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